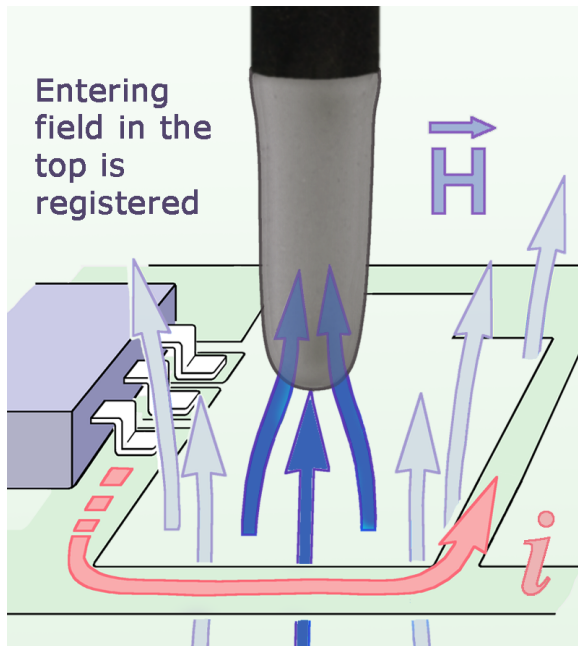


XFS-B 3-1

Scanner Probe 30 MHz up to 6 GHz



Short description

The measuring coil of the XFS-B 3-1 magnetic field scanner probe is arranged orthogonally to the probe shaft. By positioning the probe head vertically, the measurement coil touches the surface of the printed circuit board directly. This allows for use at places on the surface of printed circuit boards, which are typically hard to access, e.g. between large components of switching controllers.

The XFS-B 3-1 is a passive near-field probe which detects magnetic field lines emitted from the measured object at 90°. Magnetic field lines which enter the probe laterally are not detected.

In contrast to the XFS-R 3-1 H-field scanner probe, its coil is positioned in the probe tip at a 90° angle.

The near-field probe is small and handy. It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The H-field probe has an internal terminating resistance.

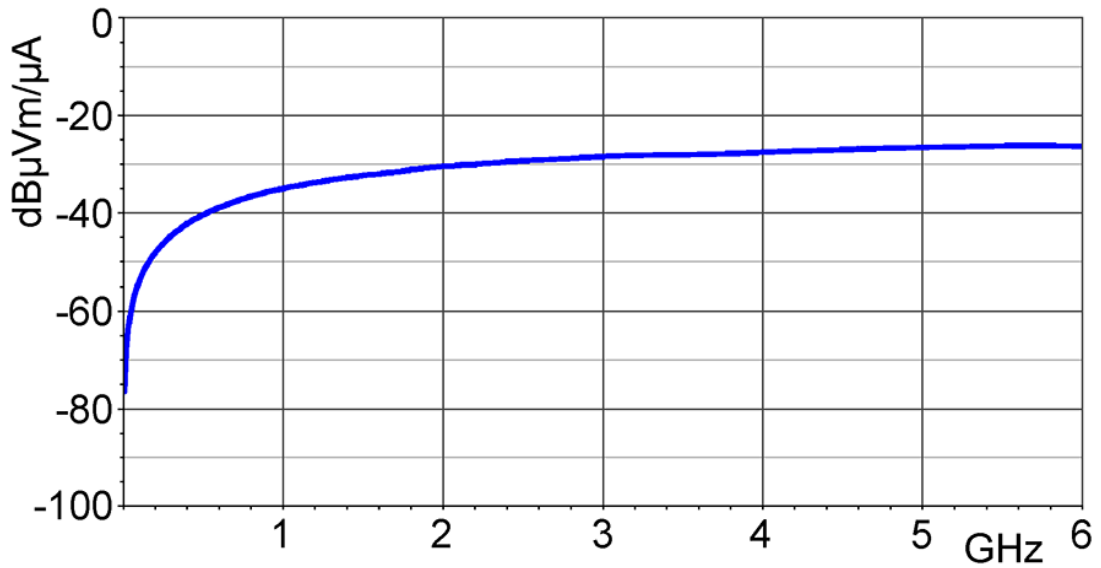
Technical parameters

| | |
|-----------------------|------------------|
| Frequency range | 30 MHz ... 6 GHz |
| Resolution | ≈ 2 mm |
| Probe head dimensions | Ø ≈ 4 mm |
| Connector - output | SMA, male, jack |

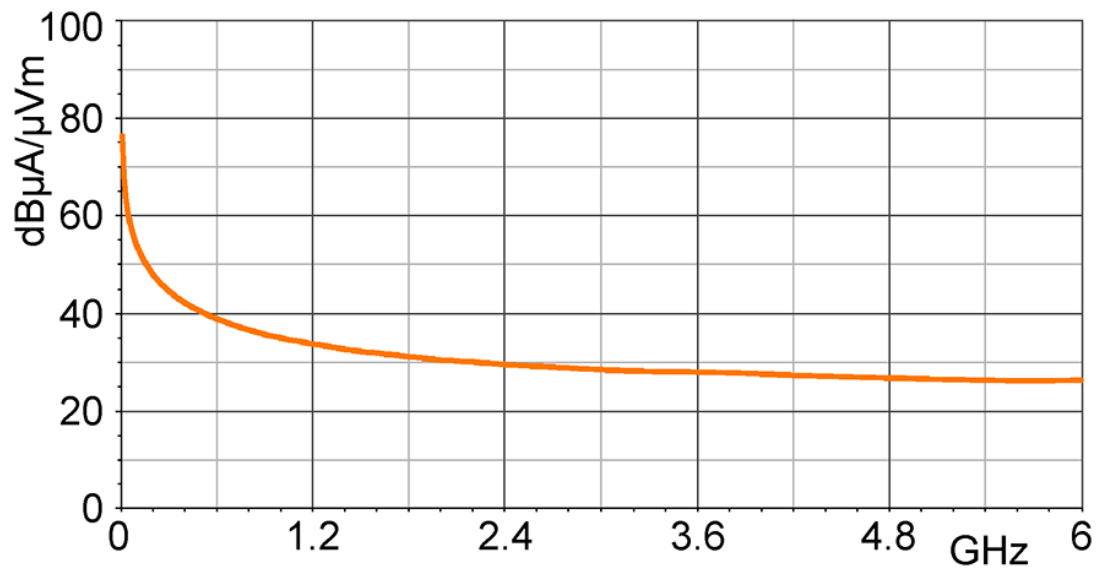
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Frequency response [dB μ V] / [dB μ A/m]



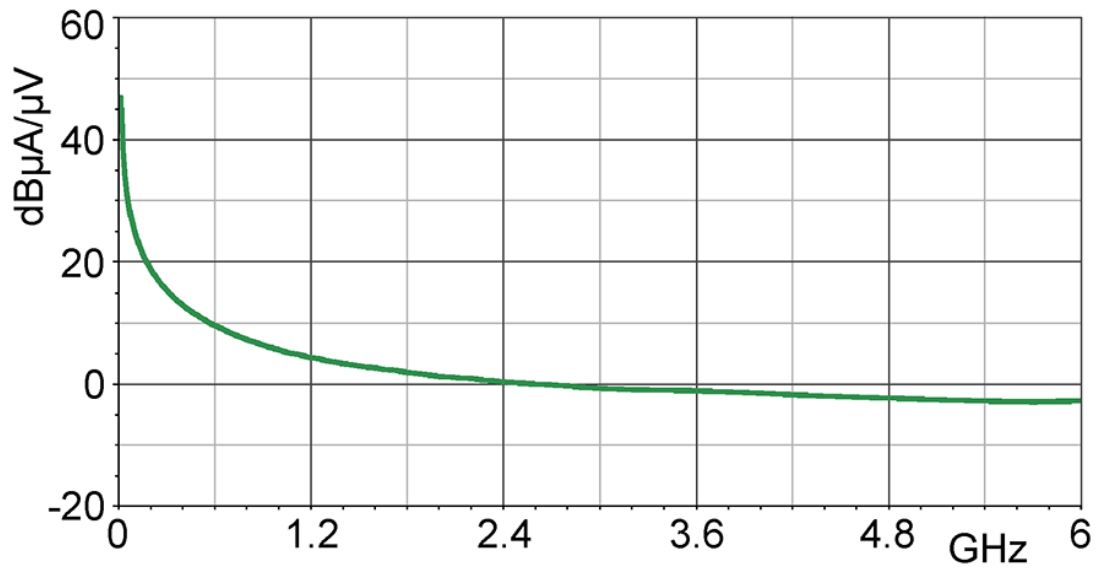
H-field correction curve [dB μ A/m] / [dB μ V]



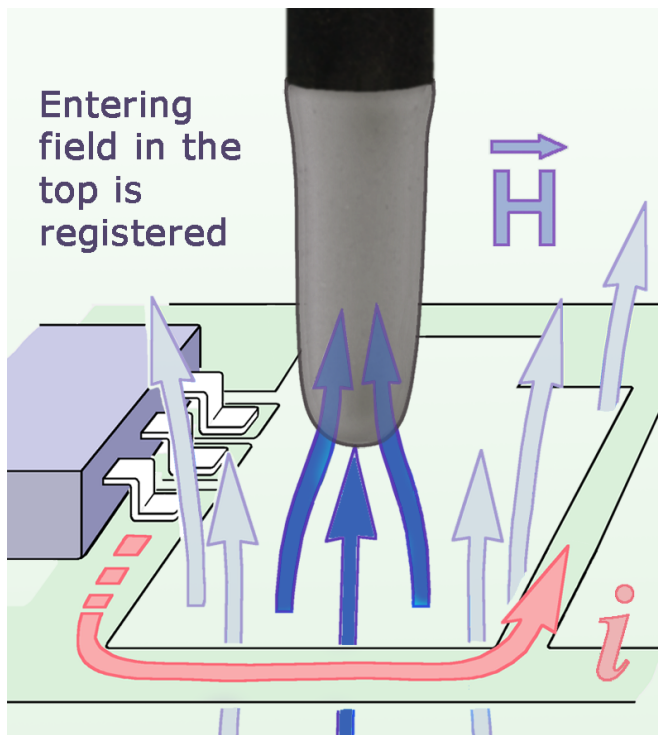
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Current correction curve [dB μ A] / [dB μ V]



Measuring principles



XFS-B 3-1

Scanner Probe 30 MHz up to 6 GHz

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